

General Description

This planar stripe MOSFET has better characteristics, such as fast switching time, low on resistance, low gate charge and excellent avalanche characteristics. It is mainly suitable for electronic ballast and switching mode power supplies.

FEATURES

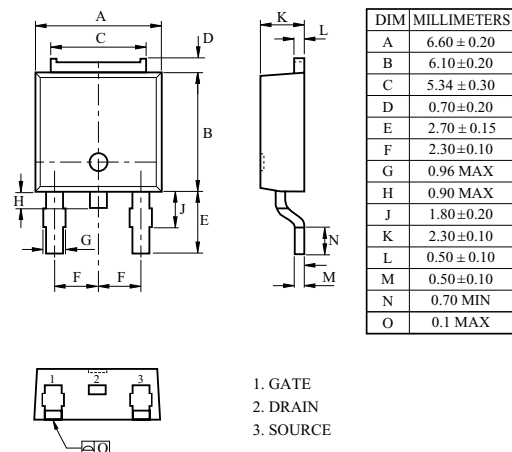
- $V_{DS} = 800V$, $I_D = 1.2A$
- Drain-Source ON Resistance :
 $R_{DS(ON)} = 16\Omega$ (Max), @ $V_{GS} = 10V$
- $Q_g = 7.0nC$ (typ.)

MAXIMUM RATING (Ta=25 °C)

CHARACTERISTIC		SYMBOL	RATING		UNIT
			KHB1D2N80D	KHB1D2N80I	
Drain-Source Voltage		V _{DSS}	800		V
Gate-Source Voltage		V _{GSS}	± 30		V
Drain Current	@T _C =25	I _D	1.2		A
	@T _C =100		0.75		
	Pulsed (Note1)	I _{DP}	4.8		
Single Pulsed Avalanche Energy (Note 2)		E _{AS}	130		mJ
Repetitive Avalanche Energy (Note 1)		E _{AR}	5.0		mJ
Peak Diode Recovery dv/dt (Note 3)		dv/dt	4.0		V/ns
Drain Power Dissipation	Ta=25	P _D	50		W
	Derate above 25		0.36		W/
Maximum Junction Temperature		T _j	150		
Storage Temperature Range		T _{stg}	-55 150		
Thermal Characteristics					
Thermal Resistance, Junction-to-Case		R _{thJC}	2.5		/W
Thermal Resistance, Case-to-Sink		R _{thCS}	50		/W
Thermal Resistance, Junction-to-Ambient		R _{thJA}	110		/W

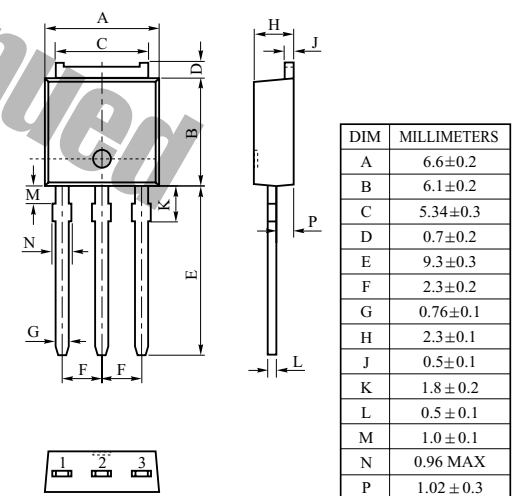
* : Mounted on the minimum pad size recommended(PCB Mount)

KHB1D2N80D

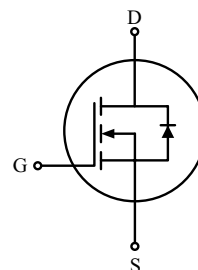


DPAK (1)

KHB1D2N80I



IPAK(1)



KHB1D2N80D/I

ELECTRICAL CHARACTERISTICS (Ta=25 °C)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Static						
Drain-Source Breakdown Voltage	BV _{DSS}	I _D =250 μA, V _{GS} =0V	800	-	-	V
Breakdown Voltage Temperature Coefficient	Δ BV _{DSS} / Δ T _j	I _D =250 μA, Referenced to 25	-	1.0	-	V/
Gate Threshold Voltage	V _{th}	V _{DS} =V _{GS} , I _D =250 μA	3.0	3.75	5.0	V
Drain Cut-off Current	I _{DSS}	V _{DS} =800V, V _{GS} =0V,	-	-	10	μA
		V _{DS} =640V, V _{GS} =0V, T _C = 125	-	-	100	
Gate Leakage Current	I _{GSS}	V _{GS} = ± 30V, V _{DS} =0V	-	-	± 100	nA
Drain-Source ON Resistance	R _{DS(ON)}	V _{GS} =10V, I _D =0.6A	-	13	16	Ω
Dynamic						
Total Gate Charge	Q _g	V _{DS} =640V, I _D =1.2A V _{GS} =10V (Note4,5)	-	7.0	-	nC
Gate-Source Charge	Q _{gs}		-	1.5	-	
Gate-Drain Charge	Q _{gd}		-	4.0	-	
Turn-on Delay time	t _{d(on)}	V _{DD} =400V R _G =25 Ω I _D =1.2A (Note4,5)	-	35	-	ns
Turn-on Rise time	t _r		-	90	-	
Turn-off Delay time	t _{d(off)}		-	40	-	
Turn-off Fall time	t _f		-	90	-	
Input Capacitance	C _{iss}	V _{DS} =25V, V _{GS} =0V, f=1.0MHz	-	170	-	pF
Output Capacitance	C _{oss}		-	25	-	
Reverse Transfer Capacitance	C _{rss}		-	3	-	
Source-Drain Diode Ratings						
Continuous Source Current	I _S	V _{GS} <V _{th}	-	-	1.2	A
Pulsed Source Current	I _{SP}		-	-	4.8	
Diode Forward Voltage	V _{SD}	I _S = 1.2A, V _{GS} =0V	-	-	1.5	V
Reverse Recovery Time	t _{rr}	I _S = 1.2A, V _{GS} =0V,	-	300	-	ns
Reverse Recovery Charge	Q _{rr}	dI _S /dt=100A/ μs	-	600	-	μC

Note 1) Repetivity rating : Pulse width limited by junction temperature.

Note 2) $L=170mH, I_S=1.2A, V_{DD}=50V, R_G=25\Omega$, Starting $T_j=25^\circ C$.

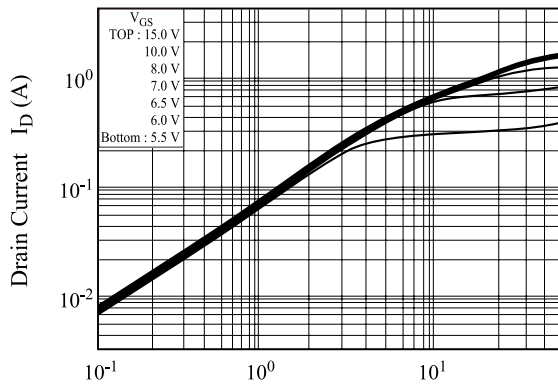
Note 3) $I_S \leq 1.2A, dI/dt \leq 300A/\mu s, V_{DD} \leq BV_{DSS}$, Starting $T_j=25^\circ C$.

Note 4) Pulse Test : Pulse width $\leq 300\mu s$, Duty Cycle $\leq 2\%$.

Note 5) Essentially independent of operating temperature.

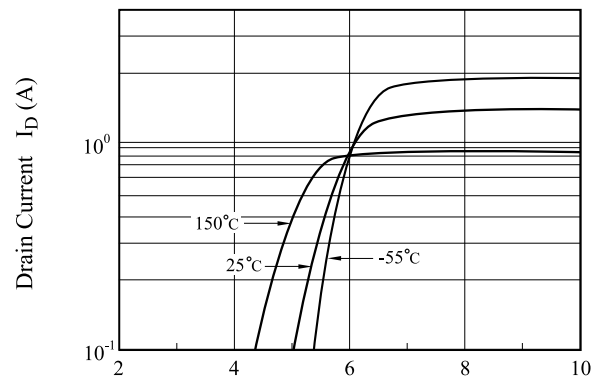
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$I_D - V_{DS}$



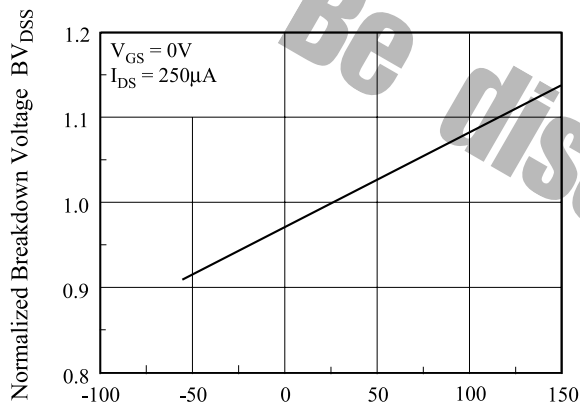
Drain - Source Voltage V_{DS} (V)

$I_D - V_{GS}$



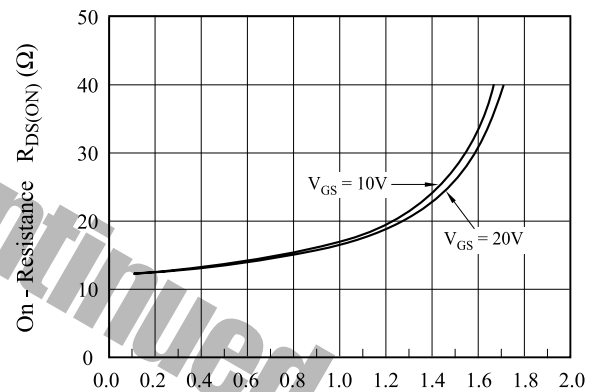
Gate - Source Voltage V_{GS} (V)

$BV_{DSS} - T_j$



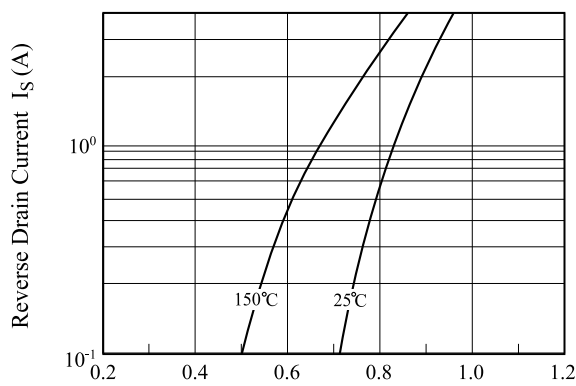
Junction Temperature T_j (°C)

$R_{DS(ON)} - I_D$



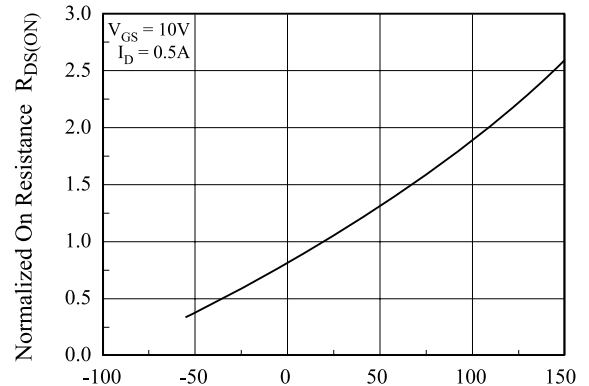
Drain Current I_D (A)

$I_{DR} - V_{SD}$



Source - Drain Voltage V_{SD} (V)

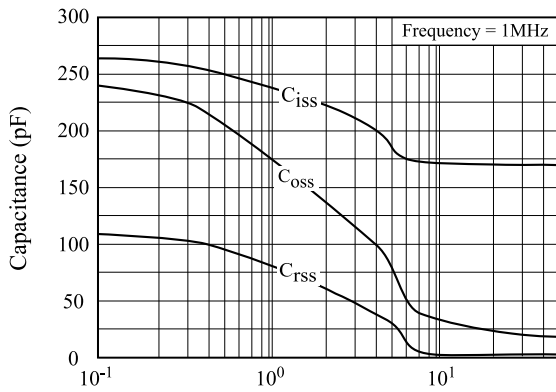
$R_{DS(ON)} - T_j$



Junction Temperature T_j (°C)

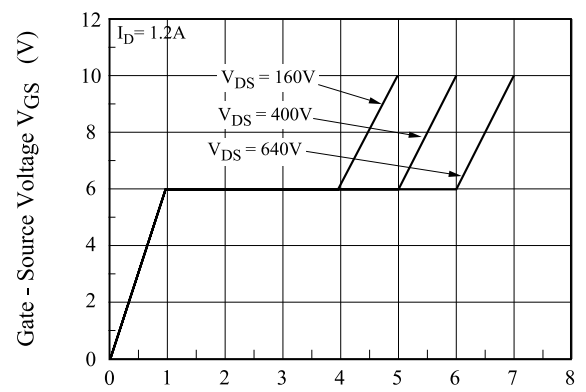
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C - V_{DS}



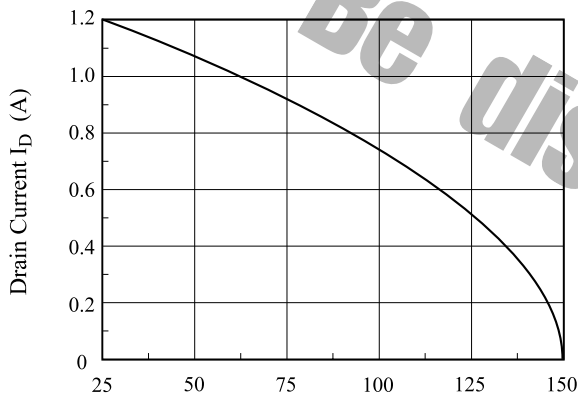
Drain - Source Voltage V_{DS} (V)

Q_g - V_{GS}



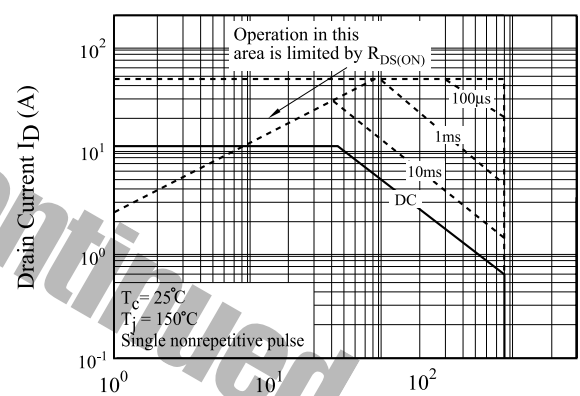
Gate - Charge Q_g (nC)

I_D - T_j



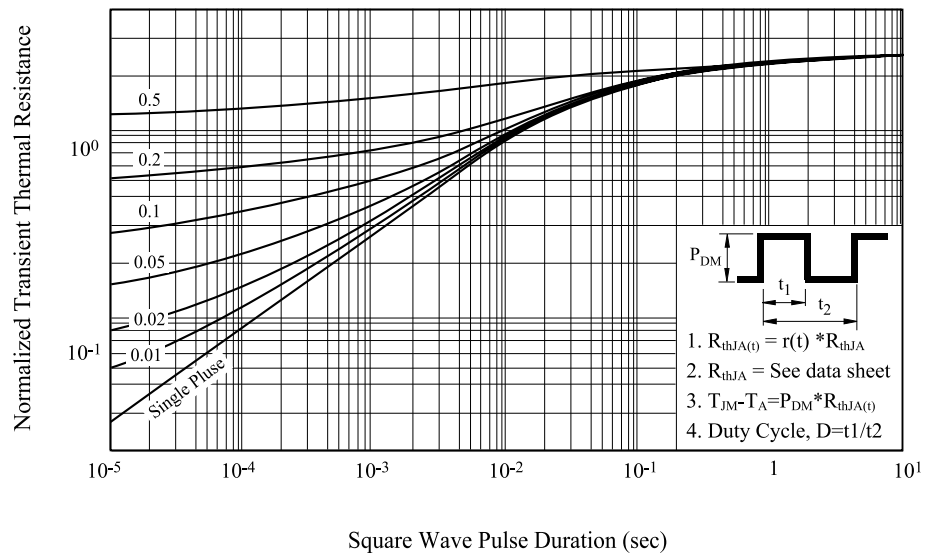
Junction Temperature T_j (°C)

Safe Operation Area



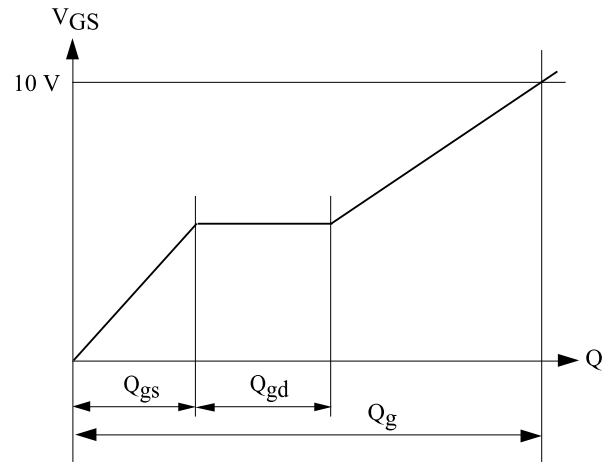
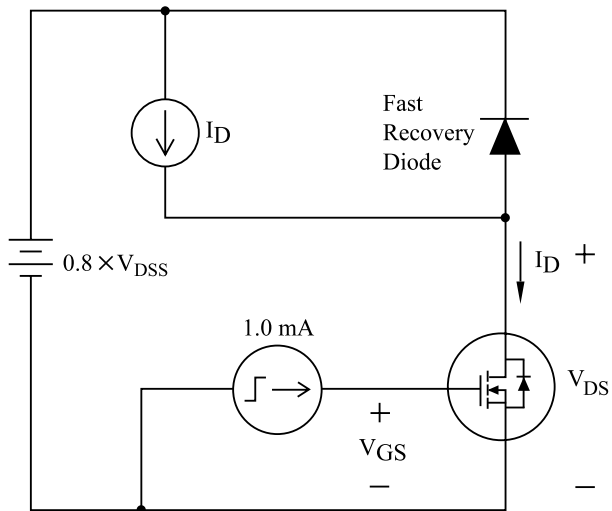
Drain - Source Voltage V_{DS} (V)

R_{th}

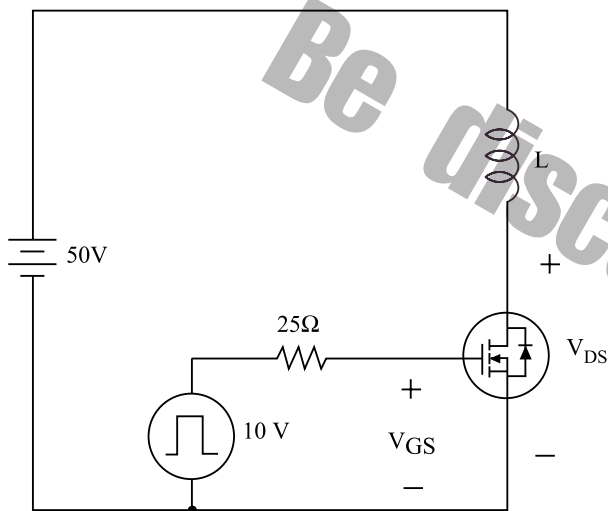


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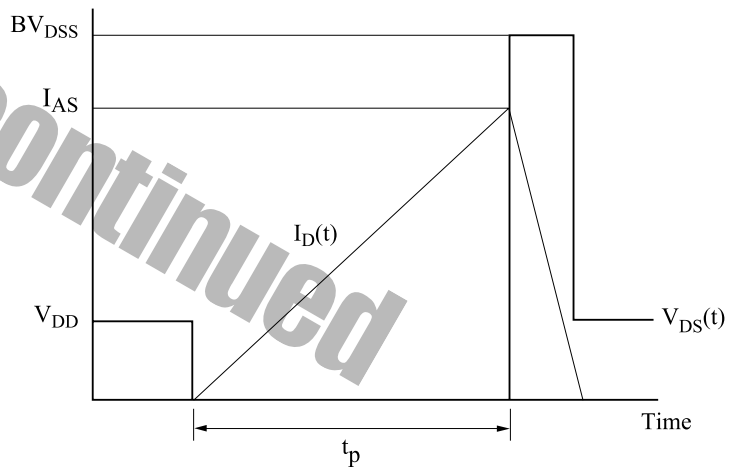
- Gate Charge



- Single Pulsed Avalanche Energy

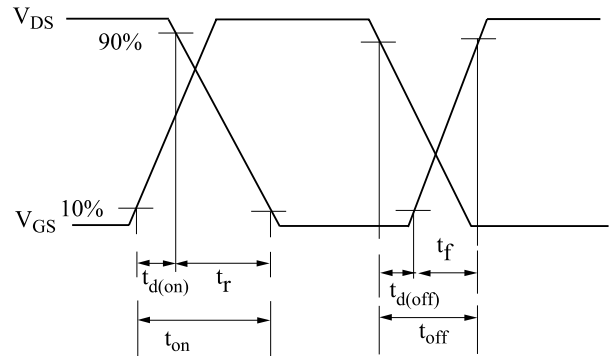
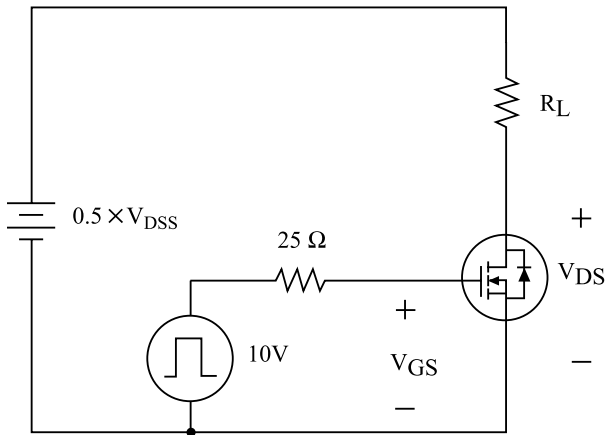


$$E_{AS} = \frac{1}{2} L I_{AS}^2 \frac{BV_{DSS}}{BV_{DSS} - V_{DD}}$$



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- Resistive Load Switching



- Source - Drain Diode Reverse Recovery and dv/dt

